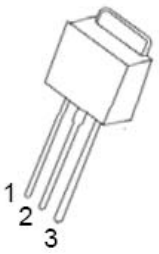
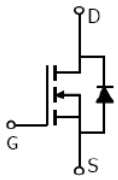
TO-251-3L Plastic-Encapsulate MOSFETS

CJD02N60 N-Channel Power MOSFET

TO-251-3L





1. GATE
2. DRAIN
3. SOURCE

General Description

The high voltage MOSFET uses an advanced termination scheme to provide enhanced voltage-blocking capability without degrading performance over time. In addition , this advanced MOSFET is designed to withstand high energy in avalanche and commutation modes . The new energy efficient design also offers a drain-to-source diode with a fast recovery time. Designed for high voltage, high speed switching applications in power suppliers, converters and PWM motor controls , these devices are particularly well suited for bridge circuits where diode speed and commutating safe operating areas are critical and offer additional and safety margin against unexpected voltage transients.

FEATURE

- Robust High Voltage Termination
- Avalanche Energy Specified
- Source-to-Drain Diode Recovery Time Comparable to a Discrete Fast Recovery Diode
- Diode is Characterized for Use in Bridge Circuits
- I_{DSS} and $V_{DS(on)}$ Specified at Elevated Temperature

Maximum ratings (T_a=25℃ unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	600	V
Gate-Source Voltage	V_{GS}	±20	
Continuous Drain Current	I_D	2	A
Pulsed Drain Current	I_{DM}	8	
Single Pulsed Avalanche Energy*	E_{AS}	128	mJ
Power Dissipation	P_D	1.25	W
Thermal Resistance from Junction to Ambient	$R_{\theta JA}$	100	℃/W
Junction Temperature	T_J	150	℃
Storage Temperature	T_{stg}	-50 ~+150	

*E_{AS} condition: T_j=25℃,V_{DD}=50V,L=64mH,I_{AS}=2A,R_G=25Ω, Starting T_J = 25°C

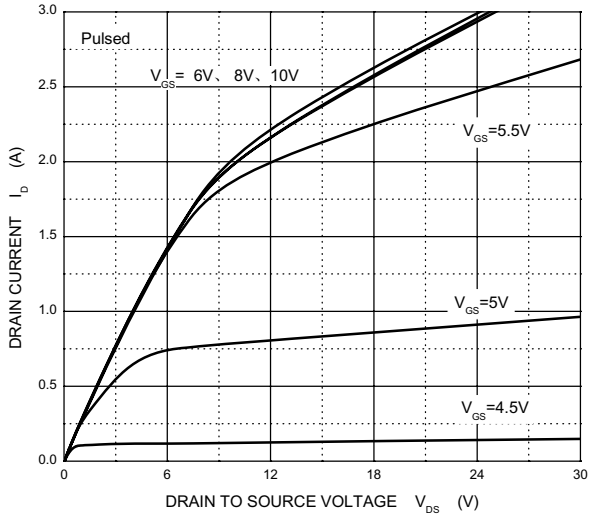
Electrical characteristics (T_a=25℃ unless otherwise noted)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Off characteristics						
Drain-source breakdown voltage	$V_{(BR)\ DSS}$	V_{GS} = 0V, I_D =250μA	600			V
Zero gate voltage drain current	I_{DSS}	V_{DS} =600V, V_{GS} =0V			25	μA
		V_{DS} =480V, V_{GS} =0V, T_j=125℃			100	
Gate-body leakage current	I_{GSS}	V_{DS} =0V, V_{GS} =±20V			±100	nA
On characteristics (note1)						
Gate-threshold voltage	$V_{GS(th)}$	V_{DS} =V_{GS}, I_D =250μA	2.0		4.0	V
Static drain-source on-resistance	$R_{DS(on)}$	V_{GS} =10V, I_D =1A		3.6	4.4	Ω
Forward transconductance	g_{FS}	V_{DS} =50V, I_D =1A	1			S
Dynamic characteristics (note 2)						
Input capacitance	C_{iss}	V_{DS} =25V,V_{GS} =0V, f =1MHz		435		pF
Output capacitance	C_{oss}			56		
Reverse transfer capacitance	C_{rss}			9.2		
Switching characteristics (note 2)						
Total gate charge	Q_g	V_{DS}=480V, V_{GS}=10V, I_D=2.4A		40	50	nC
Gate-source charge	Q_{gs}			4.2		
Gate-drain charge	Q_{gd}			8.4		
Turn-on delay time	$t_{d(on)}$	V_{DD}=300V,I_D=2A, V_{GS}=10V,R_G=18Ω		12		ns
Turn-on rise time	t_r			21		
Turn-off delay time	$t_{d(off)}$			30		
Turn-off fall time	t_f			24		
Drain-Source Diode Characteristics						
Drain-source diode forward voltage(note1)	V_{SD}	V_{GS} =0V, I_S=2A			1.6	V
Continuous drain-source diode forward current	I_S				2	A
Pulsed drain-source diode forward current	I_{SM}				8	A

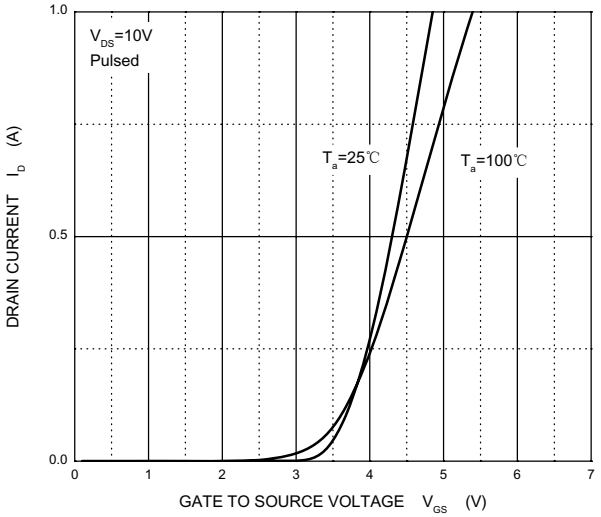
Notes:

1. Pulse Test : Pulse Width≤300μs, duty cycle ≤2%.
2. Guaranteed by design, not subject to production.

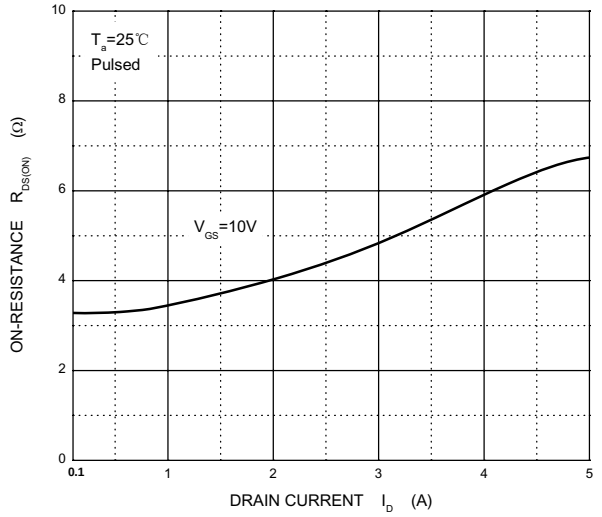
Output Characteristics



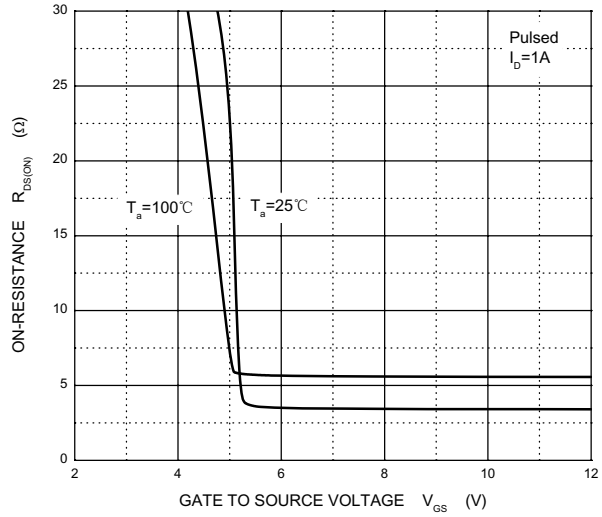
Transfer Characteristics



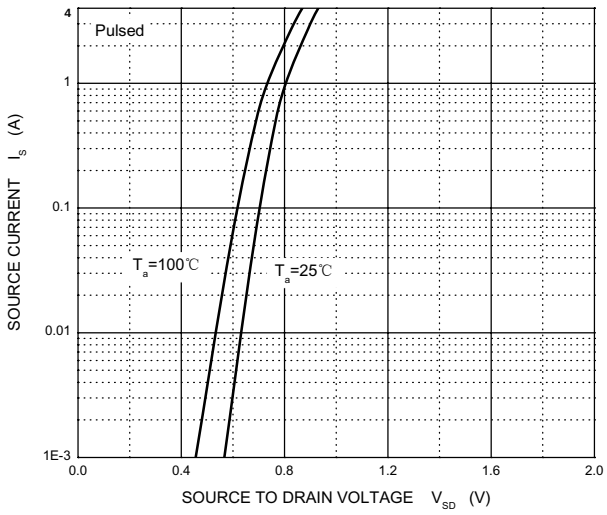
$R_{DS(ON)}$ —— I_D



$R_{DS(ON)}$ —— V_{GS}



I_S —— V_{SD}



Threshold Voltage